Se	arcn Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/647,970	CHEN, CHIH-WEI
Examiner	Art Unit
Yolanda I Wilson	2113

	SEARCHED		
Class	Subclass	Date	Examiner
714	55	3/12/2006	YLW

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See Search History	3/15/2006	YLW
714/48.ccls text searched- see serach printout	3/11/2006	YLW
714/23.ccls text searched - see search printout	3/12/2006	YLW
714/51.ccls text searched - see serach printout	3/13/2006	YLW